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Giuseppe Bruno,* Manuela Panzalorto, Francesco Nicoló and Michele Giannetto

Dip. di Chimica Inorganica, Chimica Analitica e Chimica Fisica, Universitá di Messina, 98166 Vill. Sant'Agata, Messina, Italy

Correspondence e-mail: bruno@chem.unime.it

Key indicators

Single-crystal X-ray study T = 298 KMean $\sigma(C-C) = 0.006 \text{ Å}$ Disorder in main residue R factor = 0.047 wR factor = 0.127 Data-to-parameter ratio = 12.1

For details of how these key indicators were automatically derived from the article, see http://journals.iucr.org/e.

r-1,c-2,c-3,t-4,5-Pentachloro-6-phenyltetralin

The title compound, $C_{16}H_{11}Cl_5$, is an asymmetric tetrachlorotetralin showing disorder of the alicyclic moiety, which has a boat conformation in the crystalline state and half-chair in solution. Received 13 September 2001 Accepted 9 October 2001 Online 13 October 2001

Comment

Preliminary results were presented at a National Conference (Bombieri et al., 1984). The results obtained from X-ray crystal structure analysis show that the stereochemistry of this adduct in the solid state is different from that in solution, as found from NMR studies. In fact, the asymmetric distribution of Cl atoms results in severe steric interactions within the alicyclic moiety of the molecule; these are released in solution, where the molecule is more flexible, by a distortion of the basic halfchair conformation. In the solid state, the very strict steric rigidity requirement of the system does not allow such an accommodation and the dissymmetric adduct is forced to assume a boat conformation, which minimizes steric strain and seems to better accommodate the otherwise strongly interacting c-2, c-3 and t-4 chlorine atoms. The molecule shows a disorder problem within the alicyclic ring owing to the conformational fluxionality.



Experimental

The title compound was prepared according to the procedure of Aversa *et al.* (1982). Crystals suitable for X-ray diffraction analysis were obtained by slow cooling of a light petroleum solution.

Crystal data	
$C_{16}H_{11}Cl_5$	Mo $K\alpha$ radiation
$M_r = 380.50$	Cell parameters from 30
Monoclinic, $P2_1/c$	reflections
a = 13.321 (3) Å	$\theta = 13.0{-}30.0^{\circ}$
b = 9.101 (2) Å	$\mu = 0.90 \text{ mm}^{-1}$
c = 14.279 (3) Å	T = 298 (2) K
$\beta = 112.77 \ (3)^{\circ}$	Regular prismatic, colourless
V = 1596.2 (6) Å ³	$0.31 \times 0.20 \times 0.14 \text{ mm}$
Z = 4	Crystal source: chemical synthesis
$D_{\rm r} = 1.583 {\rm Mg} {\rm m}^{-3}$	

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Data collection

Siemens R3m/V diffractometer ω -2 θ scans Absorption correction: none 2652 measured reflections 2652 independent reflections 1977 reflections with $I > 2\sigma(I)$ $\theta_{max} = 24.9^{\circ}$

Refinement

Refinement on F^2 $R[F^2 > 2\sigma(F^2)] = 0.047$ $wR(F^2) = 0.127$ S = 1.042651 reflections 219 parameters H atoms treated by a mixture of independent and constrained refinement $h = -15 \rightarrow 14$ $k = 0 \rightarrow 10$ $l = 0 \rightarrow 16$ 3 standard reflections every 197 reflections intensity decay: 1.3%

$$\begin{split} &w = 1/[\sigma^2(F_o^2) + (0.0788P)^2 \\ &+ 1.7180P] \\ &where \ P = (F_o^2 + 2F_c^2)/3 \\ (\Delta/\sigma)_{\rm max} = 0.097 \\ \Delta\rho_{\rm max} = 0.52 \ {\rm e} \ {\rm \AA}^{-3} \\ \Delta\rho_{\rm min} = -0.41 \ {\rm e} \ {\rm \AA}^{-3} \end{split}$$



Figure 1

ORTEP (Johnson, 1976) drawing of the title molecule with the atomic numbering scheme. Displacement ellipsoids are drawn at the 50% level.

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Data collection: *P3/V* (Siemens, 1989); cell refinement: *P3/V*; data reduction: *XDISK* (Siemens, 1990); program(s) used to solve structure: *SHELXS*86 (Sheldrick, 1990); program(s) used to refine structure: *SHELXL*97 (Sheldrick, 1997); molecular graphics: *XPW* (Siemens, 1996); software used to prepare material for publication: *PARST*95 (Nardelli, 1995) and *SHELXL*97.

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